Using Process-Level Redundancy to Exploit Multiple Cores for Transient Fault Tolerance

Outline

- Introduction and Motivation
- Software-centric Fault Detection
- Process-Level Redundancy
- Experimental Results
- Conclusion

Transient Faults (Soft Errors)

Transient faults are already an issue!!

- Sun Microsystems [Baumann Rel. Notes 2002]

- …

- LANL ASC Q Supercomputer [Michalak IEEE TDMR 2005]

Predicted Soft Error Rates

"The neutron SER for a latch is likely to stay constant in the future process generations…" [Karnik VLSI 2001]

Moore's Law Continues

Transient faults will be a significant issue in the design and execution of future microprocessors

Background

- One categorization: [Mukherjee HPCA 2005]
	- I. Benign Fault
	- II. Detected Unrecoverable Error (DUE)
		- False DUE- Detected fault would not have altered correctness
		- True DUE- Detected fault would have altered correctness
	- III. Silent Data Corruption (SDC)
- Hardware Approaches
	- Specialized redundant hardware, redundant multi-threading
- Software Approaches
	- Compiler solutions: instruction duplication, control flow checking
	- Low-cost, flexible alternative but higher overhead

Architectural Vulnerability Factor

- ACE—Required for Architecturally Correct Execution
- AVF—Architectural Vulnerability Factor
	- Likelihood that a transient error in a structure will lead to a computational error

- *B* is the set of all bits in some structure
- t_b is the total time that bit *b* is **ACE**
- $\triangle t$ is the total time of the execution

Benefits of Selective Protection

- Software control provides selective protection
	- Hybrid and Software systems enable software control
- Compiler/user/runtime system can make different decisions for different code regions
	- Programs, functions, or individual instructions
- Regions have different levels of natural fault resistance
- Output corrupting faults have different severity

original ipegenc output faulty jpegenc output faulty? ipegenc output*

DRACO Architecture Research Group. DSN, Edinburgh UK, 06.25.2007 **Skadron (University of Virginia)Visual Vulnerability Spectrum*Selective protection can improve reliability

Results of Injecting Errors

Fault Injection Results

- Correct range: 25% to 60% (not impacted by error injection)
- Average correct execution 33%
- Application specific trends and behaviors

Application Specific Fault Injection Results

Fault Injection Results

Function Analysis Experimental Results (164.gzip)

• Per-function (top 10 function executed per application)

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- Compiler optimization can change 5-10% of CORRECT category
- transient fault tolerant nature of code
DSN, Edinburgh UK, 06.25.2007 • Currently looking into correlation between compilation/optimization and

Fault Timeline Experimental Results

Timeline of Error Injections

- Error injections into equal time segments
- Percentage of injections resulting in CORRECT execution

Fault Timeline Experimental Results

- Analysis of fault susceptibility over time
	- Injection of errors in equal time segments of applications

Use software to leverage available hardware parallelism for low-overhead transient fault tolerance.

Software-centric Fault Detection

Processor SoR

Hardware-centric Software-centric

- Most previous approaches are hardware-centric
	- Even compiler approaches (e.g. EDDI, SWIFT)
- Software-centric able to leverage strengths of a software approach
	- Correctness is defined by software output
	- Ability to see larger scope effect of a fault
	- Ignore benign faults

Process-Level Redundancy (PLR)

System Call Emulation Unit (SCEU)

- Enforces SoR with input replication and output comparison
- System call emulation for determinism
- Detects and recovers from transient faults

Enforcing SoR

- **Input Replication**
	- All read events: read(), gettimeofday(), getrusage(), etc.
	- Return value from all system calls
- **Output Comparison**
	- All write events: write(), msync(), etc.
	- System call parameters

Maintaining Determinism

Redundant

Maintaining Determinism

- Master process executes system call
- Slave processes emulate it
	- Ignore some: rename(), unlink()
	- Execute similar/altered system call
		- Identical address space: mmap()
		- Process-specific data: open(), lseek()
- Challenges we do not handle yet
	- Shared memory
	- Asynchronous signals
	- Multi-threading

Fault Detection/Recovery

• PLR supports detection/recovery from multiple faults by increasing number of redundant processes and scaling the majority vote logic

Windows of Vulnerability

- Fault during PLR execution
- Fault during execution of operating system

Experimental Methodology

- Set of *SPEC2000* benchmarks
- Prototype developed with Intel Pin dynamic binary instrumentation tool
	- Use Pin Probes API to intercept system calls
- Register Fault Injection (*SPEC2000* test inputs)
	- 1000 random test cases per benchmark generated from an instruction profile
		- Test case: a specific bit in a source/dest register in a particular instruction invocation
	- Insert fault with Pin IARG_RETURN_REGS instruction instrumentation
	- specdiff in SPEC2000 harness determines output correctness
- PLR Performance (*SPEC2000* ref inputs)
	- 4-way SMP, 3.00Ghz Intel Xeon MP 4096KB L3 cache, 6GB memory
	- Red Hat Enterprise Linux AS release 4

Fault Injection Results

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Fault Injection Results w/ PLR

PLR Performance

- As a comparison: SWIFT is .4x slowdown for detection and 2x slowdown for detection+recovery
- **Contention Overhead**: Overhead of running multiple processes using shared resources (caches, bus, etc)
- **Emulation Overhead**: Overhead of PLR synchronization, shared memory transfers, etc.

Conclusion

- Present a software-implemented transient fault tolerance technique to utilize general-purpose hardware with multiple cores
- Differentiate between hardware-centric and software-centric fault detection models
	- Show how software-centric can be effective in ignoring benign faults
- Prototype PLR system runs on a 4-way SMP machine with 16.9% overhead for detection and 41.1% overhead with recovery

Questions?

Extra Slides

Predicted Soft Error Rates

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